

FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)



Atty Docket No. : 12177/13401
Serial No. : 09/557,672
Inventors : Michael K. BRAND et al.
Filed : April 25, 2000
Group Art Unit : 2128
Examiner : Thai Q. PHAN

U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Issue Date</u>	<u>Inventor(s)</u>
<u>T.P.</u>	6,816,813	11-2004	Tan et al.
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<u>T.P.</u>	Military Standard MIL-STD-690C. March 26, 1993.
<u>T.P.</u>	Hobbs, Gregg. "What HALT and HASS Can Do For Your Products". copyright 1997, Nelson Publishing
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<u>T.P.</u>	Linear Technology, "Reliability Assurance Program", especially p. 11. Undated. www.linear.com/company/quality/RAPweb.pdf . Printed by Examiner on 12/27/04.

Thai Phan
EXAMINER SIGNATURE

4/20/05
DATE CONSIDERED

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